



1.35V DDR3L SDRAM Addendum

MT41K256M4 – 32 Meg x 4 x 8 banks
MT41K128M8 – 16 Meg x 8 x 8 banks

Description

DDR3L SDRAM (1.35V) is a low voltage version of the DDR3 SDRAM (1.5V). Unless stated otherwise, DDR3L SDRAM meet the functional and timing specifications listed in the equivalent density DDR3 SDRAM data sheet located on www.micron.com.

Features

- $V_{DD} = V_{DDQ} = +1.35V$ (1.283V to 1.45V)
- Backward-compatible to $V_{DD} = V_{DDQ} = +1.5V \pm 0.075V$
- Differential bidirectional data strobe
- 8n-bit prefetch architecture
- Differential clock inputs (CK, CK#)
- 8 internal banks
- Nominal and dynamic on-die termination (ODT) for data, strobe, and mask signals
- CAS (READ) latency (CL): 6, 7, or 8
- Posted CAS additive latency (AL): 0, CL - 1, CL - 2
- CAS (WRITE) latency (CWL): 5, 6, 7, 8, based on t_{CK}
- Fixed burst length (BL) of 8 and burst chop (BC) of 4 (via the mode register set [MRS])
- Selectable BC4 or BL8 on-the-fly (OTF)
- Self refresh mode

- T_C of 0°C to +95°C
 - 64ms, 8192-cycle refresh at 0°C to +85°C
 - 32ms at +85°C to +95°C
- Self refresh temperature (SRT)
- Automatic self refresh (ASR)
- Write leveling
- Multipurpose register
- Output driver calibration

Options¹

- Configuration
 - 256 Meg x 4
 - 128 Meg x 8
- FBGA package (Pb-free) – x4, x8
 - 78-ball FBGA (8mm x 11.5mm) Rev. F
- Timing – cycle time
 - 1.875ns @ CL = 7 (DDR3-1066)
 - 1.5ns @ CL = 9 (DDR3-1333)
- Revision

Marking

256M4	
128M8	
JP	
-187E	
-15E	
:F	

Note: 1. Not all options listed can be combined to define an offered product. Use the part catalog search on <http://www.micron.com> for available offerings.

Table 1: Key Timing Parameters

Speed Grade	Data Rate (MT/s)	Target t_{RCD} - t_{RP} -CL (ns)	t_{RCD} (ns)	t_{RP} (ns)	CL (ns)
-187E	1066	7-7-7	13.1	13.1	13.1
-15E ¹	1333	9-9-9	13.5	13.5	13.5

Note: 1. Backward compatible to 1066, CL = 7 (-187E).

Table 2: Addressing

Parameter	256 Meg x 4	128 Meg x 8
Configuration	32 Meg x 4 x 8 banks	16 Meg x 8 x 8 banks
Refresh count	8K	8K
Row address	16K A[13:0]	16K A[13:0]
Bank address	8 BA[2:0]	8 BA[2:0]
Column address	2K A[11, 9:0]	1K A[9:0]



1Gb: x4, x8 DDR3L SDRAM Addendum Ball Assignments and Descriptions

Ball Assignments and Descriptions

Figure 1: 78-Ball FBGA – x4, x8 Ball Assignments (Top View)

	1	2	3	4	5	6	7	8	9
A	V _{SS}	V _{DD}	NC				NF, NF/TDQS#	V _{SS}	V _{DD}
B	V _{SS}	V _{SSQ}	DQ0				DM, DM/TDQS	V _{SSQ}	V _{DDQ}
C	V _{DDQ}	DQ2	DQ5				DQ1	DQ3	V _{SSQ}
D	V _{SSQ}	NF, DQ6	DQ5#				V _{DD}	V _{SS}	V _{SSQ}
E	V _{REFDQ}	V _{DDQ}	NF, DQ4				NF, DQ7	NF, DQ5	V _{DDQ}
F	NC	V _{SS}	RAS#				CK	V _{SS}	NC
G	ODT	V _{DD}	CAS#				CK#	V _{DD}	CKE
H	NC	CS#	WE#				A10/AP	ZQ	NC
J	V _{SS}	BA0	BA2				NC	V _{REFCA}	V _{SS}
K	V _{DD}	A3	A0				A12/BC#	BA1	V _{DD}
L	V _{SS}	A5	A2				A1	A4	V _{SS}
M	V _{DD}	A7	A9				A11	A6	V _{DD}
N	V _{SS}	RESET#	A13				NC	A8	V _{SS}

- Notes:
- Ball descriptions listed in Table 3 (page 3) are listed as “x4, x8” if unique; otherwise, x4 and x8 are the same.
 - A comma separates the configuration; a slash defines a selectable function.
Example: D7 = NF, NF/TDQS#. NF applies to the x4 configuration only. NF/TDQS# applies to the x8 configuration only—selectable between NF or TDQS# via MRS (symbols are defined in Table 3).



1Gb: x4, x8 DDR3L SDRAM Addendum Ball Assignments and Descriptions

Table 3: 78-Ball FBGA – x4, x8 Ball Descriptions

Symbol	Type	Description
A[9:0], A10/AP, A11, A12/BC#, A13	Input	Address inputs: Provide the row address for ACTIVATE commands, and the column address and auto precharge bit (A10) for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 sampled during a PRECHARGE command determines whether the PRECHARGE applies to one bank (A10 LOW, bank selected by BA[2:0]) or all banks (A10 HIGH). The address inputs also provide the op-code during a LOAD MODE command. Address inputs are referenced to V_{REFCA} . A12/BC#: When enabled in the mode register (MR), A12 is sampled during READ and WRITE commands to determine whether burst chop (on-the-fly) will be performed (HIGH = BL8 or no burst chop, LOW = BC4 burst chop).
BA[2:0]	Input	Bank address inputs: BA[2:0] define to which bank an ACTIVATE, READ, WRITE, or PRECHARGE command is being applied. BA[2:0] define which mode register (MR0, MR1, MR2, or MR3) is loaded during the LOAD MODE command. BA[2:0] are referenced to V_{REFCA} .
CK, CK#	Input	Clock: CK and CK# are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CK and the negative edge of CK#. Output data strobe (DQS, DQS#) is referenced to the crossings of CK and CK#.
CKE	Input	Clock enable: CKE enables (registered HIGH) and disables (registered LOW) internal circuitry and clocks on the DRAM. The specific circuitry that is enabled/disabled is dependent upon the DDR3 SDRAM configuration and operating mode. Taking CKE LOW provides PRECHARGE power-down and SELF REFRESH operations (all banks idle) or active power-down (row active in any bank). CKE is synchronous for power-down entry and exit and for self refresh entry. CKE is asynchronous for self refresh exit. Input buffers (excluding CK, CK#, CKE, RESET#, and ODT) are disabled during power-down. Input buffers (excluding CKE and RESET#) are disabled during SELF REFRESH. CKE is referenced to V_{REFCA} .
CS#	Input	Chip select: CS# enables (registered LOW) and disables (registered HIGH) the command decoder. All commands are masked when CS# is registered HIGH. CS# provides for external rank selection on systems with multiple ranks. CS# is considered part of the command code. CS# is referenced to V_{REFCA} .
DM	Input	Input data mask: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with the input data during a write access. Although the DM ball is input-only, the DM loading is designed to match that of the DQ and DQS balls. DM is referenced to V_{REFDQ} . DM has an optional use as TDQS on the x8 device.
ODT	Input	On-die termination: ODT enables (registered HIGH) and disables (registered LOW) termination resistance internal to the DDR3 SDRAM. When enabled in normal operation, ODT is only applied to each of the following balls: DQ[7:0], DQS, DQS#, and DM for the x8; DQ[3:0], DQS, DQS#, and DM for the x4. The ODT input is ignored if disabled via the LOAD MODE command. ODT is referenced to V_{REFCA} .
RAS#, CAS#, WE#	Input	Command inputs: RAS#, CAS#, and WE# (along with CS#) define the command being entered and are referenced to V_{REFCA} .
RESET#	Input	Reset: RESET# is an active LOW CMOS input referenced to V_{SS} . The RESET# input receiver is a CMOS input defined as a rail-to-rail signal with DC HIGH $\geq 0.8 \times V_{DDQ}$ and DC LOW $\leq 0.2 \times V_{DDQ}$. RESET# assertion and deassertion are asynchronous.
DQ[3:0]	I/O	Data input/output: Bidirectional data bus for the x4 configuration. DQ[3:0] are referenced to V_{REFDQ} .



1Gb: x4, x8 DDR3L SDRAM Addendum Ball Assignments and Descriptions

Table 3: 78-Ball FBGA – x4, x8 Ball Descriptions (Continued)

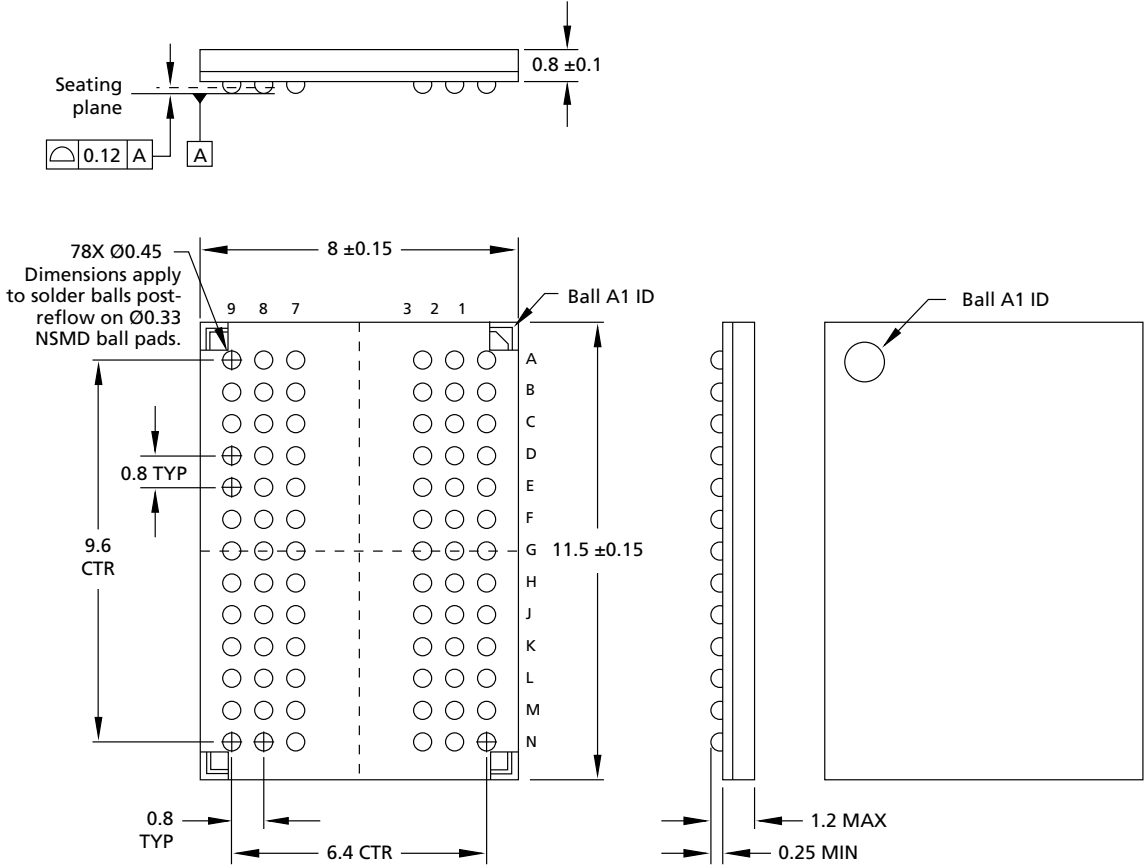
Symbol	Type	Description
DQ[7:0]	I/O	Data input/output: Bidirectional data bus for the x8 configuration. DQ[7:0] are referenced to V_{REFDQ} .
DQS, DQS#	I/O	Data strobe: Output with read data. Edge-aligned with read data. Input with write data. Center-aligned to write data.
TDQS, TDQS#	I/O	Termination data strobe: Applies to the x8 configuration only. When TDQS is enabled, DM is disabled, and the TDQS and TDQS# balls provide termination resistance.
V_{DD}	Supply	Power supply: 1.35V, 1.2825V to 1.45V operational; compatible to 1.5V operation.
V_{DDQ}	Supply	DQ power supply: 1.35V, 1.2825V to 1.45V operational; compatible with 1.5V operation.
V_{REFCA}	Supply	Reference voltage for control, command, and address: V_{REFCA} must be maintained at all times (including self refresh) for proper device operation.
V_{REFDQ}	Supply	Reference voltage for data: V_{REFDQ} must be maintained at all times (including self refresh) for proper device operation.
V_{SS}	Supply	Ground.
V_{SSQ}	Supply	DQ ground: Isolated on the device for improved noise immunity.
ZQ	Reference	External reference ball for output drive calibration: This ball is tied to an external 240 Ω resistor (RZQ), which is tied to V_{SSQ} .
NC	–	No connect: These balls should be left unconnected (the ball has no connection to the DRAM or to other balls).
NF	–	No function: When configured as a x4 device, these balls are NF. When configured as a x8 device, these balls are defined as TDQS#, DQ[7:4].



1Gb: x4, x8 DDR3L SDRAM Addendum Package Dimensions

Package Dimensions

Figure 2: 78-Ball FBGA – x4, x8; Die Rev. F, "JP"



Note: 1. All dimensions are in millimeters.



1Gb: x4, x8 DDR3L SDRAM Addendum Electrical Characteristics – I_{DD} Specifications

Electrical Characteristics – I_{DD} Specifications

Table 4: I_{DD} Maximum Limits – Rev. F

Speed Bin		DDR3L-1066	DDR3L-1333	Units
I _{DD}	Width			
I _{DD0}	x4	65	75	mA
	x8	85	95	mA
I _{DD1}	x4	80	90	mA
	x8	100	110	mA
I _{DD2P0}	All	8	10	mA
I _{DD2P1}	All	25	30	mA
I _{DD2Q}	All	45	55	mA
I _{DD2N}	All	45	55	mA
I _{DD2NT}	All	65	75	mA
I _{DD3P}	All	30	37	mA
I _{DD3N}	x4, x8	50	60	mA
I _{DD4R}	x4	120	145	mA
	x8	120	145	mA
I _{DD4W}	x4	120	145	mA
	x8	120	145	mA
I _{DD5B}	All	175	185	mA
I _{DD6}	All	6	6	mA
I _{DD6ET}	All	9	9	mA
I _{DD7}	x4	230	300	mA
	x8	290	360	mA
I _{DD8}	All	I _{DD2P0} + 2mA	I _{DD2P0} + 2mA	mA



Electrical Specifications

Table 5: Input/Output Capacitance

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

CapacitanceParameters	Symbol	DDR3L-800		DDR3L-1066		DDR3L-1333		Units
		Min	Max	Min	Max	Min	Max	
Single-end I/O: DQ, DM	C_{IO}	1.5	2.5	1.5	2.5	1.5	2.5	pF
Differential I/O: DQS, DQS#, TDQS, TDQS#	C_{IO}	1.5	2.5	1.5	2.5	1.5	2.5	pF
Inputs (CTRL, CMD, ADDR)	C_I	0.75	1.3	0.75	1.3	0.75	1.3	pF

Table 6: DC Electrical Characteristics and Operating Conditions – 1.35V Operation

All voltages are referenced to V_{SS}

Parameter/Condition	Symbol	Min	Nom	Max	Units	Notes
Supply voltage	V_{DD}	1.283	1.35	1.45	V	1, 2, 3, 4
I/O supply voltage	V_{DDQ}	1.283	1.35	1.45	V	1, 2, 3, 4

- Notes:
1. Maximum DC value may not be greater than 1.425V. The DC value is the linear average of $V_{DD}/V_{DDQ}(t)$ over a very long period of time (e.g., 1 sec).
 2. If the maximum limit is exceeded, input levels shall be governed by DDR3 specifications.
 3. Under these supply voltages, the device operates to this DDR3L specification.
 4. Once initialized for DDR3L operation, DDR3 operation may only be used if the device is in reset while V_{DD} and V_{DDQ} are changed for DDR3 operation (see Figure 3 (page 15)).

Table 7: DC Electrical Characteristics and Operating Conditions – 1.5V Operation

All voltages are referenced to V_{SS}

Parameter/Condition	Symbol	Min	Nom	Max	Units	Notes
Supply voltage	V_{DD}	1.425	1.5	1.575	V	1, 2, 3
I/O supply voltage	V_{DDQ}	1.425	1.5	1.575	V	1, 2, 3

- Notes:
1. If the minimum limit is exceeded, input levels shall be governed by DDR3L specifications.
 2. Under 1.5V operation, this DDR3L device operates in accordance with the DDR3 specifications under the same speed timings as defined for this device.
 3. Once initialized for DDR3 operation, DDR3L operation may only be used if the device is in reset while V_{DD} and V_{DDQ} are changed for DDR3L operation (see Figure 3 (page 15)).

Table 8: Input Switching Conditions – Command and Address

Parameter/Condition	Symbol	DDR3L-800/1066/1333	Units
Input high AC voltage: Logic 1	$V_{IH(AC160)min}$	160	mV
Input high AC voltage: Logic 1	$V_{IH(AC135)min}$	135	mV
Input high DC voltage: Logic 1	$V_{IH(DC90)min}$	90	mV
Input low AC voltage: Logic 0	$V_{IL(AC160)min}$	-160	mV
Input low AC voltage: Logic 0	$V_{IL(AC135)min}$	-135	mV
Input low DC voltage: Logic 0	$V_{IL(DC90)min}$	-90	mV



1Gb: x4, x8 DDR3L SDRAM Addendum Electrical Specifications

Table 9: Input Switching Conditions – DQ and DM

Parameter/Condition	Symbol	DDR3L-800 DDR3L-1066	DDR3L-1333	Units
Input high AC voltage: Logic 1	$V_{IH(AC160)min}$	160	–	mV
Input high AC voltage: Logic 1	$V_{IH(AC135)min}$	135	135	mV
Input high DC voltage: Logic 1	$V_{IH(DC90)min}$	90	90	mV
Input low AC voltage: Logic 0	$V_{IL(AC160)min}$	–160	–	mV
Input low AC voltage: Logic 0	$V_{IL(AC135)min}$	–135	–135	mV
Input low DC voltage: Logic 0	$V_{IL(DC90)min}$	–90	–90	mV

Table 10: Differential Input Operating Conditions (CK, CK# and DQS, DQS#)

Parameter/Condition	Symbol	Min	Max	Units
Differential input logic high – slew	$V_{IH,diff(AC)slew}$	180	n/a	mV
Differential input logic low – slew	$V_{IL,diff(AC)slew}$	n/a	–180	mV
Differential input logic high	$V_{IH,diff(AC)}$	$2 \times (V_{IH(AC)} - V_{REF})$	V_{DD}/V_{DDQ}	mV
Differential input logic low	$V_{IL,diff(AC)}$	V_{SS}/V_{SSQ}	$2 \times (V_{REF} - V_{IL(AC)})$	mV
Single-ended high level for strobes	V_{SHE}	$V_{DDQ}/2 + 160$	V_{DDQ}	mV
Single-ended high level for CK, CK#		$V_{DD}/2 + 160$	V_{DD}	mV
Single-ended low level for strobes	V_{SEL}	V_{SSQ}	$V_{DDQ}/2 - 160$	mV
Single-ended low level for CK, CK#		V_{SS}	$V_{DD}/2 - 160$	mV

Table 11: Required Time t_{DVAC} for CK/CK#, DQS/DQS# Differential for AC Ringback

Slew Rate (V/ns)	t_{VAC} at 320mV (ps)	t_{VAC} at 270mV (ps)
>4.0	70	209
4.0	53	198
3.0	47	194
2.0	35	186
1.8	31	184
1.6	26	181
1.4	20	177
1.2	12	171
1.0	0	164
<1.0	0	164


Table 12: R_{TT} Effective Impedance

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

MR1 [9, 6, 2]	R _{TT}	Resistor	V _{OUT}	Min	Nom	Max	Units
0, 1, 0	120Ω	R _{TT,120PD240}	0.2 × V _{DDQ}	0.6	1.0	1.15	RZQ/1
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/1
			0.8 × V _{DDQ}	0.9	1.0	1.45	RZQ/1
		R _{TT,120PU240}	0.2 × V _{DDQ}	0.9	1.0	1.45	RZQ/1
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/1
			0.8 × V _{DDQ}	0.6	1.0	1.15	RZQ/1
	120Ω		V _{IL(AC)} to V _{IH(AC)}	0.9	1.0	1.65	RZQ/2
0, 0, 1	60Ω	R _{TT,60PD120}	0.2 × V _{DDQ}	0.6	1.0	1.15	RZQ/2
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/2
			0.8 × V _{DDQ}	0.9	1.0	1.45	RZQ/2
		R _{TT,60PU120}	0.2 × V _{DDQ}	0.9	1.0	1.45	RZQ/2
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/2
			0.8 × V _{DDQ}	0.6	1.0	1.15	RZQ/2
	60Ω		V _{IL(AC)} to V _{IH(AC)}	0.9	1.0	1.65	RZQ/4
0, 1, 1	40Ω	R _{TT,40PD80}	0.2 × V _{DDQ}	0.6	1.0	1.15	RZQ/3
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/3
			0.8 × V _{DDQ}	0.9	1.0	1.45	RZQ/3
		R _{TT,40PU80}	0.2 × V _{DDQ}	0.9	1.0	1.45	RZQ/3
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/3
			0.8 × V _{DDQ}	0.6	1.0	1.15	RZQ/3
	40Ω		V _{IL(AC)} to V _{IH(AC)}	0.9	1.0	1.65	RZQ/6
1, 0, 1	30Ω	R _{TT,30PD60}	0.2 × V _{DDQ}	0.6	1.0	1.15	RZQ/4
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/4
			0.8 × V _{DDQ}	0.9	1.0	1.45	RZQ/4
		R _{TT,30PU60}	0.2 × V _{DDQ}	0.9	1.0	1.45	RZQ/4
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/4
			0.8 × V _{DDQ}	0.6	1.0	1.15	RZQ/4
	30Ω		V _{IL(AC)} to V _{IH(AC)}	0.9	1.0	1.65	RZQ/8
1, 0, 0	20Ω	R _{TT,20PD40}	0.2 × V _{DDQ}	0.6	1.0	1.15	RZQ/6
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/6
			0.8 × V _{DDQ}	0.9	1.0	1.45	RZQ/6
		R _{TT,20PU40}	0.2 × V _{DDQ}	0.9	1.0	1.45	RZQ/6
			0.5 × V _{DDQ}	0.9	1.0	1.15	RZQ/6
			0.8 × V _{DDQ}	0.6	1.0	1.15	RZQ/6
	20Ω		V _{IL(AC)} to V _{IH(AC)}	0.9	1.0	1.65	RZQ/12


Table 13: Reference Settings for ODT Timing Measurements

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

Measured Parameter	$R_{TT,nom}$ Setting	$R_{TT(WR)}$ Setting	Vsw1	Vsw2
t_{AON}	RZQ/4 (60 Ω)	n/a	50mV	100mv
	RZQ/12 (20 Ω)	n/a	100mV	200mV
t_{AOF}	RZQ/4 (60 Ω)	n/a	50mV	100mv
	RZQ/12 (20 Ω)	n/a	100mV	200mV
t_{AONPD}	RZQ/4 (60 Ω)	n/a	50mV	100mv
	RZQ/12 (20 Ω)	n/a	100mV	200mV
t_{AOFPD}	RZQ/4 (60 Ω)	n/a	50mV	100mv
	RZQ/12 (20 Ω)	n/a	100mV	200mV
t_{ADC}	RZQ/12 (20 Ω)	RZQ/2 (20 Ω)	200mV	250mV

Table 14: 34 Ω Driver Impedance Characteristics

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

MR1 [5, 1]	R_{ON}	Resistor	V_{OUT}	Min	Nom	Max ¹	Units
0, 1	34.3 Ω	$R_{ON,34PD}$	$0.2 \times V_{DDQ}$	0.6	1.0	1.15	RZQ/7
			$0.5 \times V_{DDQ}$	0.9	1.0	1.15	RZQ/7
			$0.8 \times V_{DDQ}$	0.9	1.0	1.45	RZQ/7
		$R_{ON,34PU}$	$0.2 \times V_{DDQ}$	0.9	1.0	1.45	RZQ/7
			$0.5 \times V_{DDQ}$	0.9	1.0	1.15	RZQ/7
			$0.8 \times V_{DDQ}$	0.6	1.0	1.15	RZQ/7
Pull-up/pull-down mismatch (MM_{PUPD})			$V_{IL(AC)}$ to $V_{IH(AC)}$	-10	n/a	10	%

Note: 1. A larger Max limit will result in slightly lower minimum currents.

Table 15: 40 Ω Driver Impedance Characteristics

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

MR1 [5, 1]	R_{ON}	Resistor	V_{OUT}	Min	Nom	Max ¹	Units
0, 0	40 Ω	$R_{ON,40PD}$	$0.2 \times V_{DDQ}$	0.6	1.0	1.15	RZQ/6
			$0.5 \times V_{DDQ}$	0.9	1.0	1.15	RZQ/6
			$0.8 \times V_{DDQ}$	0.9	1.0	1.45	RZQ/6
		$R_{ON,40PU}$	$0.2 \times V_{DDQ}$	0.9	1.0	1.45	RZQ/6
			$0.5 \times V_{DDQ}$	0.9	1.0	1.15	RZQ/6
			$0.8 \times V_{DDQ}$	0.6	1.0	1.15	RZQ/6
Pull-up/pull-down mismatch (MM_{PUPD})			$V_{IL(AC)}$ to $V_{IH(AC)}$	-10	n/a	10	%

Note: 1. A larger Max limit will result in slightly lower minimum currents.



1Gb: x4, x8 DDR3L SDRAM Addendum Electrical Specifications

Table 16: Single-Ended Output Driver Characteristics

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

Parameter/Condition	Symbol	Min	Max	Units
Output slew rate: Single-ended; For rising and falling edges, measure between $V_{OL(AC)} = V_{REF} - 0.09 \times V_{DDQ}$ and $V_{OH(AC)} = V_{REF} + 0.09 \times V_{DDQ}$	SRQ_{se}	1.75	6	V/ns

Table 17: Differential Output Driver Characteristics

Gray-shaded cells have the same values as those in the 1.5V DDR3 data sheet

Parameter/Condition	Symbol	Min	Max	Units
Output slew rate: Differential; For rising and falling edges, measure between $V_{OL,diff(AC)} = -0.18 \times V_{DDQ}$ and $V_{OH,diff(AC)} = +0.18 \times V_{DDQ}$	SRQ_{diff}	3.5	12	V/ns
Output differential crosspoint voltage	$V_{OX(AC)}$	$V_{REF} - 135$	$V_{REF} + 135$	mV

Table 18: Electrical Characteristics and AC Operating Conditions

Parameter		Symbol	DDR3L-800		DDR3L-1066		DDR3L-1333		Units
			Min	Max	Min	Max	Min	Max	
DQ Input Timing									
Data setup time to DQS, DQS#	Base (specification)	t_{DS}^{AC160}	90	–	40	–	n/a	–	ps
	V_{REF} @ 1 V/ns		250	–	200	–	n/a	–	ps
Data setup time to DQS, DQS#	Base (specification)	t_{DS}^{AC135}	140	–	90	–	45	–	ps
	V_{REF} @ 1 V/ns		275	–	225	–	180	–	ps
Data hold time from DQS, DQS#	Base (specification)	t_{DH}^{DC90}	160	–	110	–	75	–	ps
	V_{REF} @ 1 V/ns		250	–	200	–	165	–	ps
Command and Address Timing									
CTRL, CMD, ADDR setup to CK, CK#	Base (specification)	t_{IS}^{AC160}	215	–	140	–	80	–	ps
	V_{REF} @ 1 V/ns		375	–	300	–	240	–	ps
CTRL, CMD, ADDR setup to CK, CK#	Base (specification)	t_{IS}^{AC135}	365	–	290	–	205	–	ps
	V_{REF} @ 1 V/ns		500	–	425	–	340	–	ps
CTRL, CMD, ADDR hold from CK, CK#	Base (specification)	t_{IH}^{DC90}	285	–	210	–	150	–	ps
	V_{REF} @ 1 V/ns		375	–	300	–	240	–	ps


Table 19: Derating Values for t_{IS}/t_{IH} – AC160/DC90-Based

$\Delta t_{IS}, \Delta t_{IH}$ Derating (ps) – AC/DC-Based																
CMD/ADDR Slew Rate V/ns	CK, CK# Differential Slew Rate															
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}
2.0	80	45	80	45	80	45	88	53	96	61	104	69	112	79	120	95
1.5	53	30	53	30	53	30	61	38	69	46	77	54	85	64	93	80
1.0	0	0	0	0	0	0	8	8	16	16	24	24	32	34	40	50
0.9	-1	-3	-1	-3	-1	-3	7	5	15	13	23	21	31	31	39	47
0.8	-3	-8	-3	-8	-3	-8	5	1	13	9	21	17	29	27	37	43
0.7	-5	-13	-5	-13	-5	-13	3	-5	11	3	19	11	27	21	35	37
0.6	-8	-20	-8	-20	-8	-20	0	-12	8	-4	16	4	24	14	32	30
0.5	-20	-30	-20	-30	-20	-30	-12	-22	-4	-14	4	-6	12	4	20	20
0.4	-40	-45	-40	-45	-40	-45	-32	-37	-24	-29	-16	-21	-8	-11	0	5

Table 20: Derating Values for t_{IS}/t_{IH} – AC135/DC90-Based

$\Delta t_{IS}, \Delta t_{IH}$ Derating (ps) – AC/DC-Based																
CMD/ADDR Slew Rate V/ns	CK, CK# Differential Slew Rate															
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}
2.0	68	45	68	45	45	45	76	53	84	61	92	69	100	79	108	95
1.5	45	30	45	30	30	30	53	38	61	46	69	54	77	64	85	80
1.0	0	0	0	0	0	0	8	8	16	16	24	24	32	34	40	50
0.9	2	-3	2	-3	2	-3	10	5	18	13	26	21	34	31	42	47
0.8	3	-8	3	-8	3	-8	11	1	19	9	27	17	35	27	43	43
0.7	6	-13	6	-13	6	-13	14	-5	22	3	30	11	38	21	46	37
0.6	9	-20	9	-20	9	-20	17	-12	25	-4	33	4	41	14	49	30
0.5	5	-30	5	-30	5	-30	13	-22	21	-14	29	-6	37	4	45	20
0.4	-3	-45	-3	-45	-3	-45	6	-37	14	-29	22	-21	30	-11	38	5

Table 21: Required Time t_{VAC} Above $V_{IH(AC)}$ (Below $V_{IL(AC)}$) for Valid ADD/CMD Transition

Slew Rate (V/ns)	t_{VAC} at 160mV (ps)	t_{VAC} at 135mV (ps)
>2.0	70	209
2.0	53	198
1.5	47	194
1.0	35	186
0.9	31	184
0.8	26	181



1Gb: x4, x8 DDR3L SDRAM Addendum Electrical Specifications

Table 21: Required Time t_{VAC} Above $V_{IH(AC)}$ (Below $V_{IL(AC)}$) for Valid ADD/CMD Transition (Continued)

Slew Rate (V/ns)	t_{VAC} at 160mV (ps)	t_{VAC} at 135mV (ps)
0.7	20	177
0.6	12	171
0.5	0	164
<0.5	0	164

Table 22: Derating Values for t_{DS}/t_{DH} – AC160/DC90-Based

$\Delta t_{DS}, \Delta t_{DH}$ Derating (ps) – AC/DC-Based																
DQ Slew Rate V/ns	DQS, DQS# Differential Slew Rate															
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}
2.0	80	45	80	45	80	45										
1.5	53	30	53	30	53	30	61	38								
1.0	0	0	0	0	0	0	8	8	16	16						
0.9			-1	-3	-1	-3	7	5	15	13	23	21				
0.8					-3	-8	5	1	13	9	21	17	29	27		
0.7							-3	-5	11	3	19	11	27	21	35	37
0.6									8	-4	16	4	24	14	32	30
0.5											4	6	12	4	20	20
0.4													-8	-11	0	5

Table 23: Derating Values for t_{DS}/t_{DH} – AC135/DC90-Based

$\Delta t_{DS}, \Delta t_{DH}$ Derating (ps) – AC/DC-Based																
DQ Slew Rate V/ns	DQS, DQS# Differential Slew Rate															
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}
2.0	68	45	68	45	68	45										
1.5	45	30	45	30	45	30	53	38								
1.0	0	0	0	0	0	0	8	8	16	16						
0.9			2	-3	2	-3	10	5	18	13	26	21				
0.8					3	-8	11	1	19	9	27	17	35	27		
0.7							14	-5	22	3	30	11	38	21	46	37
0.6									25	-4	33	4	41	14	49	30
0.5											39	-6	37	4	45	20
0.4													30	-11	38	5


Table 24: Required Time t_{VAC} Above $V_{IH(AC)}$ (Below $V_{IL(AC)}$) for Valid DQ Transition

Slew Rate (V/ns)	t_{VAC} at 160mV (ps)	t_{VAC} at 135mV (ps)
>2.0	70	109
2.0	53	98
1.5	47	94
1.0	35	86
0.9	31	84
0.8	26	81
0.7	20	77
0.6	12	71
0.5	0	64
<0.5	0	64

Initialization

If the SDRAM is powered up and initialized for the 1.35V operating voltage range, voltage may be increased to the 1.5V operation range provided:

- Just prior to increasing the 1.35V operating voltages, no further commands are issued, other than NOPs or COMMAND INHIBITs, and all banks are in the precharge state
- The 1.5V operating voltages are stable prior to issuing new commands, other than NOPs or COMMAND INHIBITs
- The DLL is reset and relocked after the 1.5V operating voltages are stable and prior to any READ command
- The ZQ calibration is performed, t_{ZQinit} must be satisfied after the 1.5V operating voltages are stable and prior to any READ command

If the SDRAM is powered up and initialized for the 1.5V operating voltage range, voltage may be reduced to the 1.35V operation range provided:

- Just prior to reducing the 1.5V operating voltages, no further commands are issued, other than NOPs or COMMAND INHIBITs, and all banks are in the precharge state
- The 1.35V operating voltages are stable prior to issuing new commands, other than NOPs or COMMAND INHIBITs
- The DLL is reset and relocked after the 1.35V operating voltages are stable and prior to any READ command
- The ZQ calibration is performed, t_{ZQinit} must be satisfied after the 1.35V operating voltages are stable and prior to any READ command

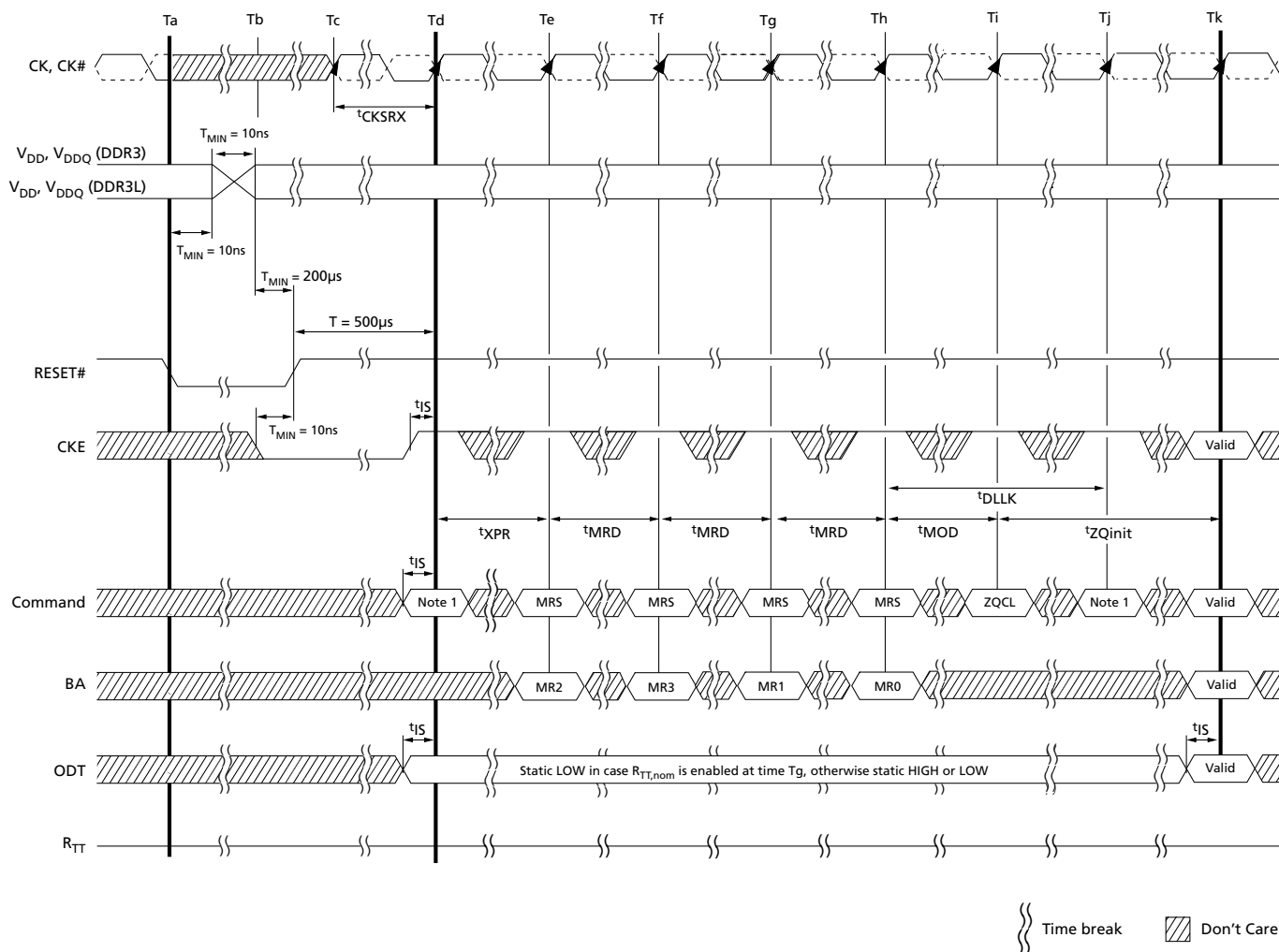


1Gb: x4, x8 DDR3L SDRAM Addendum Initialization

V_{DD} Voltage Switching

After the DDR3L DRAM is powered up and initialized, the power supply can be altered between the DDR3L and DDR3 levels, provided the sequence in Figure 3 is maintained.

Figure 3: V_{DD} Voltage Switching



Note: 1. From time point "Td" until "Tk," NOP or DES commands must be applied between MRS and ZQCL commands.

8000 S. Federal Way, P.O. Box 6, Boise, ID 83707-0006, Tel: 208-368-3900
 www.micron.com/productsupport Customer Comment Line: 800-932-4992
 Micron and the Micron logo are trademarks of Micron Technology, Inc.
 All other trademarks are the property of their respective owners.

This data sheet contains initial characterization limits that are subject to change upon full characterization of production devices.